




<p style="text-align: center;"><b>Searched</b></p> 	<p>Application/Control No.</p> <p>10531299</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>KIM ET AL.</p>
	<p>Examiner</p> <p>Jaisle, Cecilia M</p>	<p>Art Unit</p> <p>1624</p>

Class	SubClass	Date	Examiner
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<b>Search Notes</b>  	Application/Control No.  10531299	Applicant(s)/Patent Under Reexamination  KIM ET AL.
	Examiner Jaisle, Cecilia M	Art Unit 1624

Notes	Date	Examiner
Searched in STN by STIC	07/12/2006	<i>Cecilia Jaisle</i>
Inventor Search done	7/19/06	<i>Cecilia Jaisle</i>
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<b>Interference Searched</b>  	Application/Control No.  10531299	Applicant(s)/Patent Under Reexamination  KIM ET AL.
	Examiner Jaisle, Cecilia M	Art Unit 1624

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